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number Substitute for form 1449B/PTO	Complete if Known		
INFORMATION DISCLOSURE	Application Number	10/710,836	
OCT 2 7 2004 MENT BY APPLICANT	Filing Date	August 5, 2004	
Date Spritted: October 22, 2004	First Named Inventor	M. Brandon Steele	
Date Sphritted, October 22, 2004	Group Art Unit	2812	
(use as many sheets as necessary)	Examiner Name		
Sheelan in of 3	Attorney Docket Number	023228-0115	

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Examiner	Cite	U.S. Patent D		Name of Patentee or Applicant of	Date of Publication of	Pages, Columns, Lines, Where Relevant
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¹ Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁸Applicant is to place a check mark here if English language Translation is attached.

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	INFORMATI	ON DISCLO	SURE	Application Number	10/710,836		
	STATEMEN	T BY APPL	ICANT	Filing Date	August 5, 2004		
	Data Cubmitta	d. Ostobor 1	22 2004	First Named Inventor	M. Brandon Steele		
	Date Submitte	ea: October a	22, 2004	Group Art Unit	2812-7863		
(use as many sheets as necessary)				Examiner Name			
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Examiner Signature	Meagan Walling	Date Considered	ulylos

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	INFORMAT	ION DISCLO	SURE	Application Number	10/710,836		
STATEMENT BY APPLICANT				Filing Date	August 5, 2004		
Date Submitted: October 22, 2004				First Named Inventor	M. Brandon Steele		
	Date Submitte	ea: October 2	2, 2004	Group Art Unit	20127863		
	(use as many	sheets as ne	cessary)	Examiner Name			
Sheet	3	of	3	Attorney Docket Number	023228-0115		

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Examiner Signature	Meagan Walling	Date Considered	ntulos

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number Substitute for form 1449B/PTO			
INFORMATION DISCLOSURE	Application Number	10/710,836	
JAN 2 7 2005	Filing Date	08/05/2004	
JAN 2 7 2005	First Named Inventor	M. Brandon Steele	
Date Submitted: January 20, 2005	Group Art Unit	- 2077 2863	
(use as many sheets as necessary)	Examiner Name		
Sheet 1 of 2	Attorney Docket Number	023228-0115	

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	6.4-	U.S. Patent Document		Name of Patentee or Applicant of	Date of Publication of	Pages, Columns, Lines, Where Relevant			
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	INFORMATIO	N DISCLO	SUR		·Application Number	10/710,836	
	STATEMENT	BY APPLI	CANT	lan .	Filing Date	08/05/2004	
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Sheet	2	of	2	PADEMARK	Attorney Docket Number	023228-0115	

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Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁶
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	Æ	/ ate Submitted: Oct	oher i	5 2005	First Named Inventor	M. Brandon Steele	
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